Hyper- and Multi-Spectral Imaging

Guest Editor:

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Message from the Guest Editor

Dear Colleagues,

Spectral Imaging (SI) combines the advantages of both imaging and spectroscopy (high spatial and spectral resolution) in a single instrument. In SI, light intensity is recorded as a function of both wavelength and location. The output is a three-dimensional data structure known as spectral cube, with each pixel representing the spectrum of the scene at that point. Most recent developments include snapshot or single exposure SI cameras, which capture the images of the spectral cube simultaneously or, alternatively, spectral cube streams at nearly video rates. Dynamic SI implies that light intensity can now be recorded as a function of time, wavelength, polarization, two or more spatial locations, etc.

We invite investigators to contribute original research articles, as well as review articles, that will stimulate the continuing efforts in the field of SI.

Prof. Costas Balas

Guest Editor

Keywords: Hyper-Spectral Imaging; Multi-Spectral Imaging; Snap-Shot Spectral Imaging; Spectral Cube Data Analysis/Processing; Biomedicine; Remote sensing; Microscopy; Non-Destructive Testing

Special Issue

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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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